

**Search Notes**

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Examiner

Jason M. Han

Applicant(s)/Patent under  
Reexamination

AYNIE ET AL.

Art Unit

2875

**SEARCHED**

Class	Subclass	Date	Examiner
362	516-523	3/3/2005	JMH
362	459-460	3/3/2005	JMH
362	487	3/3/2005	JMH
362	498	3/3/2005	JMH
362	507-509	3/3/2005	JMH
362	514	3/3/2005	JMH
362	540	3/3/2005	JMH
362	548-549	3/3/2005	JMH
362	326-327	3/3/2005	JMH

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Search Update	3/3/2005	JMH
P.E. John Ward	3/3/2005	JMH